



PMEG6010ELR

60 V, 1 A low leakage current Schottky barrier rectifier

8 November 2013

Preliminary data sheet

1. General description

Planar Maximum Efficiency General Application (MEGA) Schottky barrier rectifier with an integrated guard ring for stress protection, encapsulated in a SOD123W small and flat lead Surface-Mounted Device (SMD) plastic package.

2. Features and benefits

- Average forward current: $I_{F(AV)} \leq 1$ A
- Reverse voltage: $V_R \leq 60$ V
- Extremely low leakage current
- Low forward voltage
- High power capability due to clip-bonding technology
- Small and flat lead SMD plastic package
- AEC-Q101 qualified
- High temperature $T_j \leq 175$ °C

3. Applications

- Low voltage rectification
- High efficiency DC-to-DC conversion
- Switch mode power supply
- Reverse polarity protection
- Low power consumption applications

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{F(AV)}$	average forward current	$\delta = 0.5$; $f = 20$ kHz; $T_{sp} \leq 170$ °C; square wave	-	-	1	A
V_R	reverse voltage	$T_j = 25$ °C	-	-	60	V
V_F	forward voltage	$I_F = 1$ A; $T_j = 25$ °C	-	605	660	mV
I_R	reverse current	$T_j = 25$ °C; $V_R = 60$ V; $t_p \leq 300$ μ s; $\delta \leq 0.02$; pulsed	-	90	300	nA



5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode[1]	 <p>SOD123W</p>	 <i>sym001</i>
2	A	anode		

[1] The marking bar indicates the cathode.

6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PMEG6010ELR	SOD123W	plastic surface mounted package; 2 leads	SOD123W

7. Marking

Table 4. Marking codes

Type number	Marking code
PMEG6010ELR	K1

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_R	reverse voltage	$T_j = 25\text{ °C}$		-	60	V
I_F	forward current	$T_{sp} = 165\text{ °C}$		-	1.41	A
$I_{F(AV)}$	average forward current	$\delta = 0.5$; $f = 20\text{ kHz}$; $T_{amb} \leq 140\text{ °C}$; square wave	[1]	-	1	A
		$\delta = 0.5$; $f = 20\text{ kHz}$; $T_{sp} \leq 170\text{ °C}$; square wave		-	1	A
I_{FSM}	non-repetitive peak forward current	$t_p = 8\text{ ms}$; $T_{j(init)} = 25\text{ °C}$; square wave		-	50	A
P_{tot}	total power dissipation	$T_{amb} \leq 25\text{ °C}$	[2]	-	680	mW
			[3]	-	1150	mW
			[1]	-	2140	mW
T_j	junction temperature			-	175	°C
T_{amb}	ambient temperature			-55	175	°C
T_{stg}	storage temperature			-65	175	°C

[1] Device mounted on a ceramic Printed-Circuit Board (PCB), Al_2O_3 , standard footprint.

[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

[3] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for cathode 1 cm^2 .

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1][2]	-	-	220	K/W
			[1][3]	-	-	130	K/W
			[1][4]	-	-	70	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		[5]	-	-	18	K/W

[1] For Schottky barrier diodes thermal runaway has to be considered, as in some applications the reverse power losses P_R are a significant part of the total power losses.

[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.

[3] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for cathode 1 cm^2 .

[4] Device mounted on a ceramic PCB, Al_2O_3 , standard footprint.

[5] Soldering point of cathode tab.

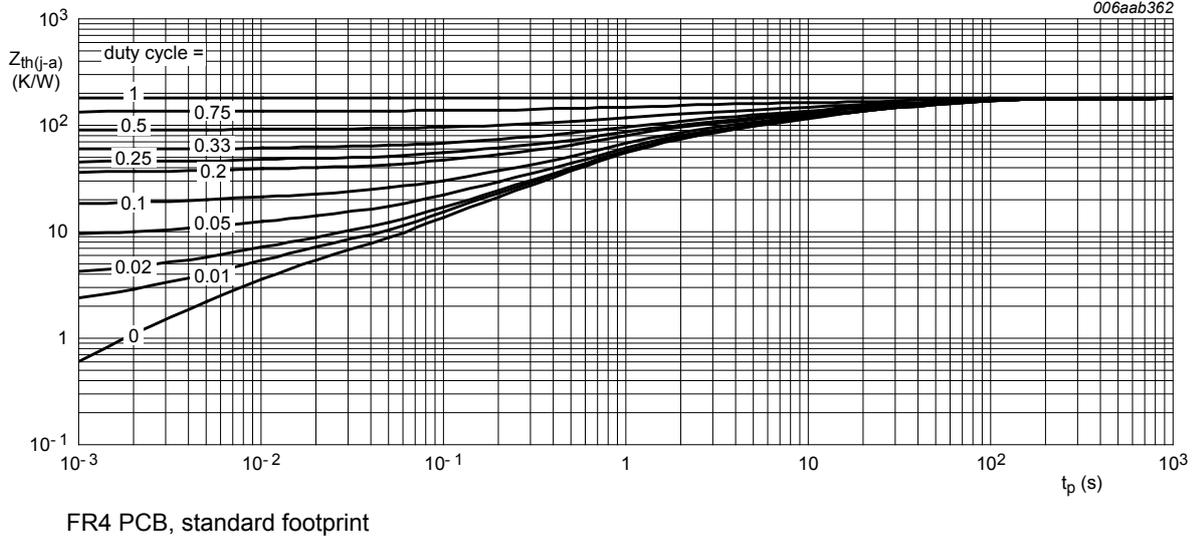


Fig. 1. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

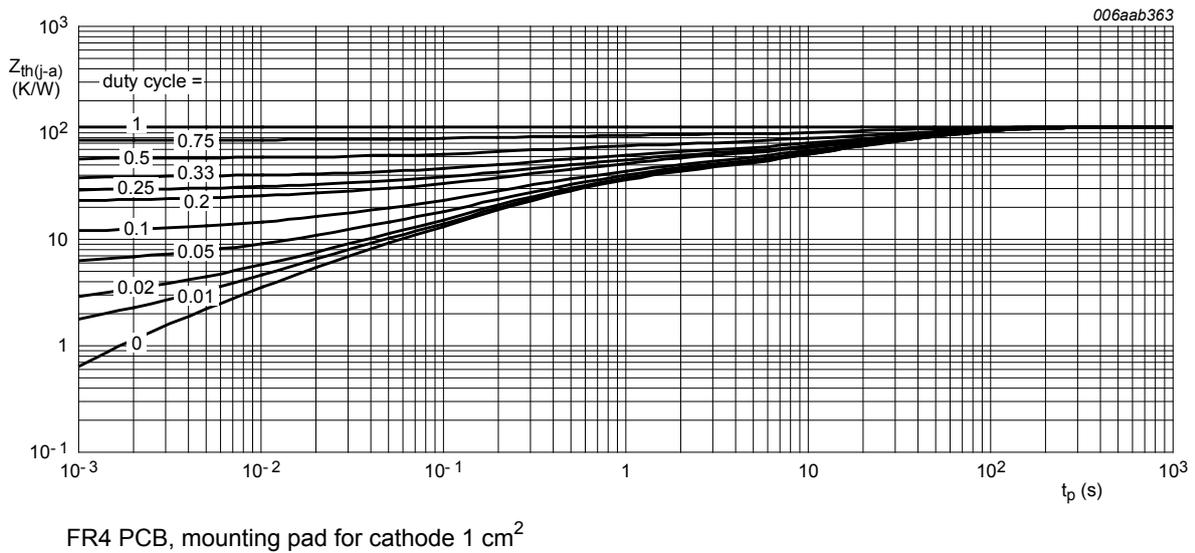
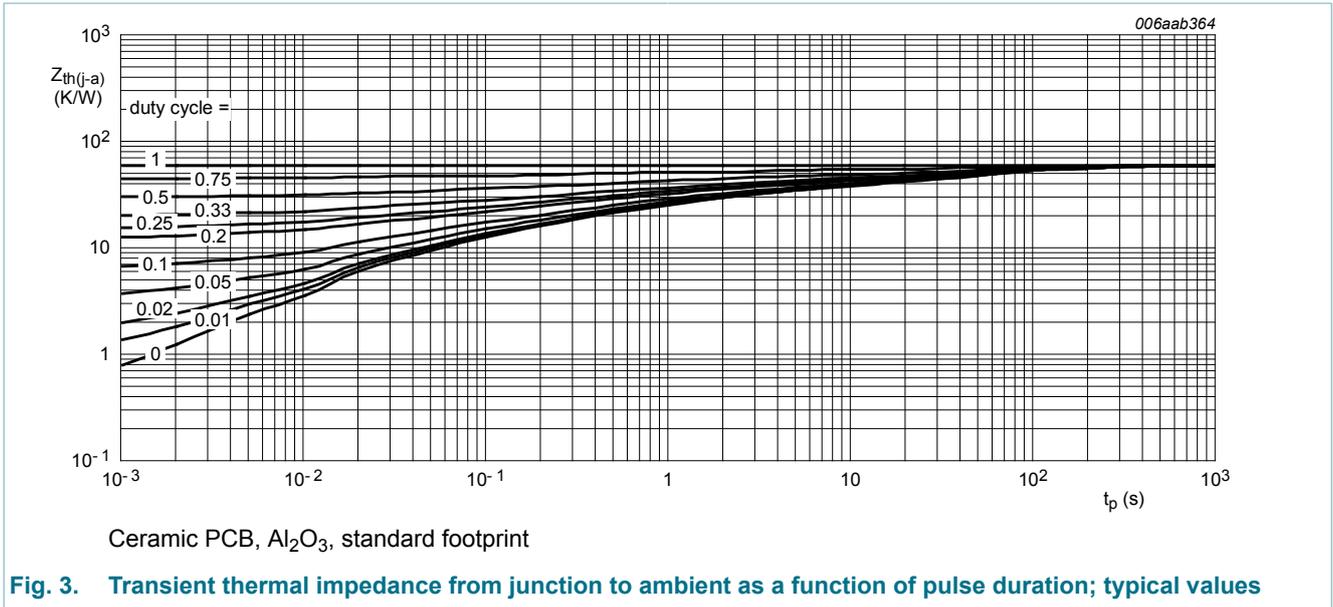


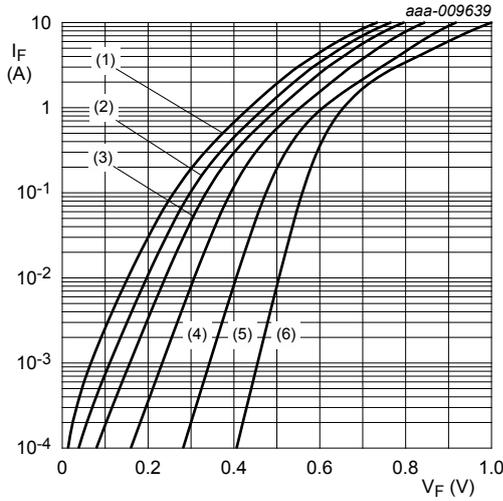
Fig. 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



10. Characteristics

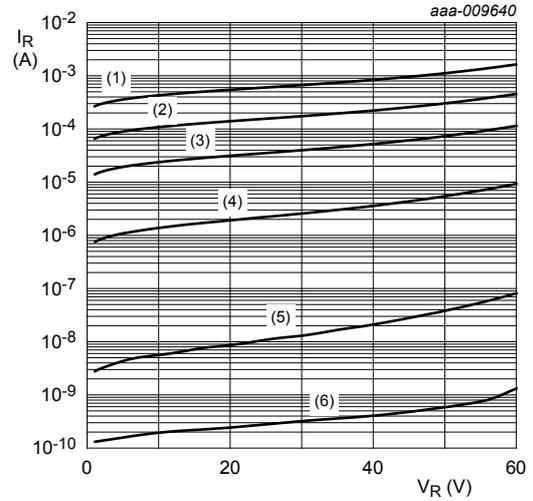
Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _F	forward voltage	I _F = 0.1 A; T _j = 25 °C	-	475	540	mV
		I _F = 0.5 A; T _j = 25 °C	-	550	605	mV
		I _F = 0.7 A; T _j = 25 °C	-	575	625	mV
		I _F = 1 A; T _j = 25 °C	-	605	660	mV
I _R	reverse current	V _R = 5 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 25 °C; pulsed	-	5	-	nA
		V _R = 10 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 25 °C; pulsed	-	6	-	nA
		V _R = 40 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 25 °C; pulsed	-	25	50	nA
		V _R = 60 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 25 °C; pulsed	-	90	300	nA
		V _R = 10 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 125 °C; pulsed	-	25	-	μA
		V _R = 60 V; t _p ≤ 300 μs; δ ≤ 0.02 ; T _j = 125 °C; pulsed	-	120	-	μA
C _d	diode capacitance	V _R = 1 V; f = 1 MHz; T _j = 25 °C	-	110	-	pF
		V _R = 4 V; f = 1 MHz; T _j = 25 °C	-	65	-	pF
		V _R = 10 V; f = 1 MHz; T _j = 25 °C	-	45	-	pF
t _{rr}	reverse recovery time	I _F = 0.5 A; I _R = 0.5 A; I _{R(meas)} = 0.1 A; T _j = 25 °C	-	4.5	-	ns
V _{FRM}	peak forward recovery voltage	I _F = 0.5 A; dI _F /dt = 20 A/μs; T _j = 25 °C	-	580	-	mV



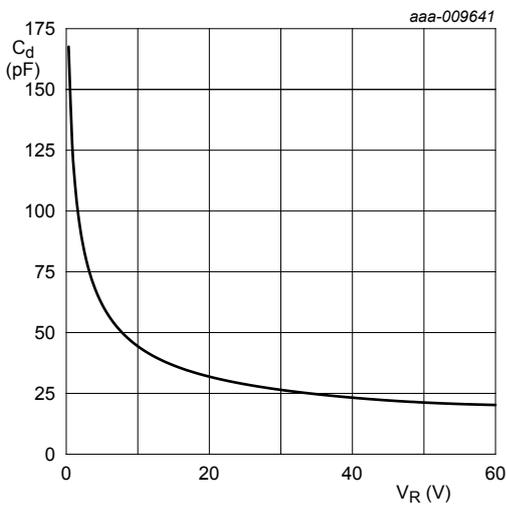
- (1) $T_j = 175\text{ }^\circ\text{C}$
- (2) $T_j = 150\text{ }^\circ\text{C}$
- (3) $T_j = 125\text{ }^\circ\text{C}$
- (4) $T_j = 85\text{ }^\circ\text{C}$
- (5) $T_j = 25\text{ }^\circ\text{C}$
- (6) $T_j = -40\text{ }^\circ\text{C}$

Fig. 4. Forward current as a function of forward voltage; typical values



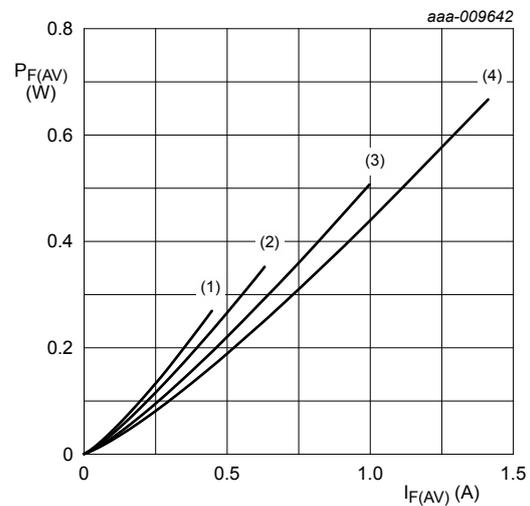
- (1) $T_j = 175\text{ }^\circ\text{C}$
- (2) $T_j = 150\text{ }^\circ\text{C}$
- (3) $T_j = 125\text{ }^\circ\text{C}$
- (4) $T_j = 85\text{ }^\circ\text{C}$
- (5) $T_j = 25\text{ }^\circ\text{C}$
- (6) $T_j = -40\text{ }^\circ\text{C}$

Fig. 5. Reverse current as a function of reverse voltage; typical values



$f = 1\text{ MHz}; T_{amb} = 25\text{ }^\circ\text{C}$

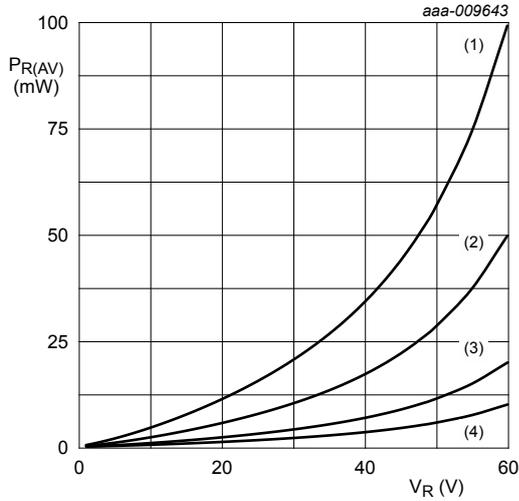
Fig. 6. Diode capacitance as a function of reverse voltage; typical values



- $T_j = 175\text{ }^\circ\text{C}$
- (1) $\delta = 0.1$
- (2) $\delta = 0.2$
- (3) $\delta = 0.5$
- (4) $\delta = 1$

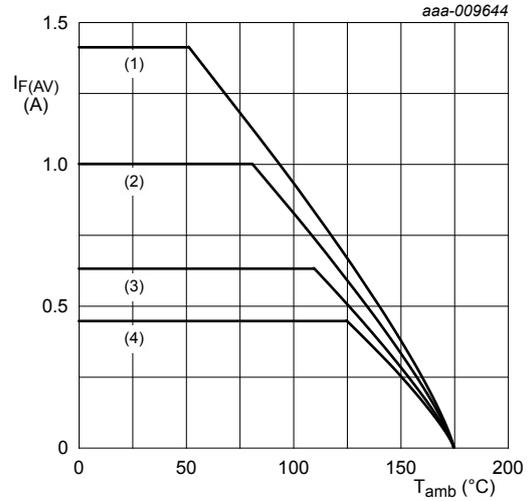
Fig. 7. Average forward power dissipation as a function of average forward current; typical values

60 V, 1 A low leakage current Schottky barrier rectifier



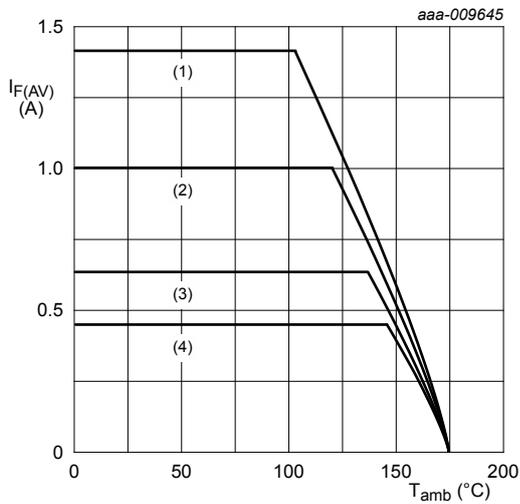
$T_j = 150\text{ }^\circ\text{C}$
 (1) $\delta = 1$
 (2) $\delta = 0.5$
 (3) $\delta = 0.2$
 (4) $\delta = 0.1$

Fig. 8. Average reverse power dissipation as a function of reverse voltage; typical values



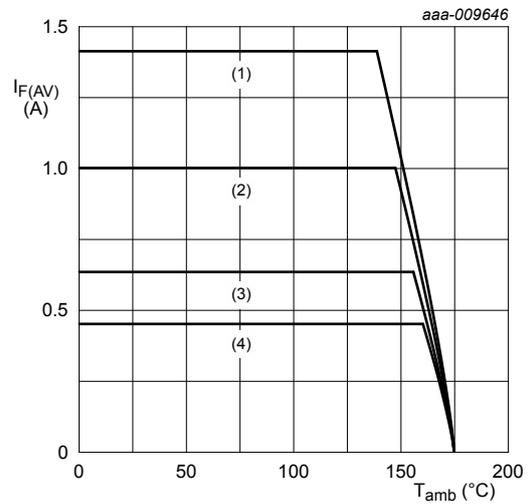
FR4 PCB, standard footprint
 $T_j = 175\text{ }^\circ\text{C}$
 (1) $\delta = 1$ (DC)
 (2) $\delta = 0.5$; $f = 20\text{ kHz}$
 (3) $\delta = 0.2$; $f = 20\text{ kHz}$
 (4) $\delta = 0.1$; $f = 20\text{ kHz}$

Fig. 9. Average forward current as a function of ambient temperature; typical values



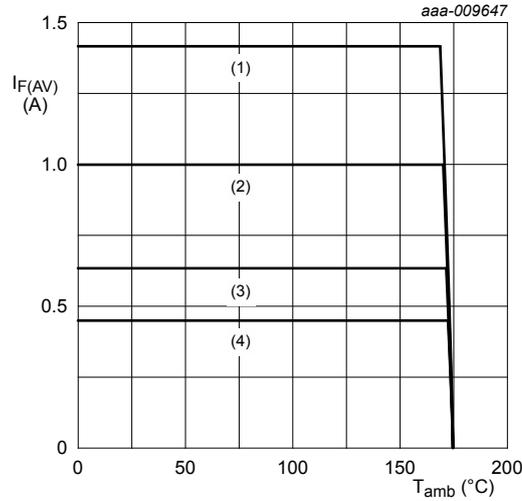
FR4 PCB, mounting pad for cathode 1 cm^2
 $T_j = 175\text{ }^\circ\text{C}$
 (1) $\delta = 1$ (DC)
 (2) $\delta = 0.5$; $f = 20\text{ kHz}$
 (3) $\delta = 0.2$; $f = 20\text{ kHz}$
 (4) $\delta = 0.1$; $f = 20\text{ kHz}$

Fig. 10. Average forward current as a function of ambient temperature; typical values



Ceramic PCB, Al_2O_3 , standard footprint
 $T_j = 175\text{ }^\circ\text{C}$
 (1) $\delta = 1$ (DC)
 (2) $\delta = 0.5$; $f = 20\text{ kHz}$
 (3) $\delta = 0.2$; $f = 20\text{ kHz}$
 (4) $\delta = 0.1$; $f = 20\text{ kHz}$

Fig. 11. Average forward current as a function of ambient temperature; typical values



$T_j = 175\text{ }^\circ\text{C}$

(1) $\delta = 1$ (DC)

(2) $\delta = 0.5$; $f = 20\text{ kHz}$

(3) $\delta = 0.2$; $f = 20\text{ kHz}$

(4) $\delta = 0.1$; $f = 20\text{ kHz}$

Fig. 12. Average forward current as a function of solder point temperature; typical values

11. Test information

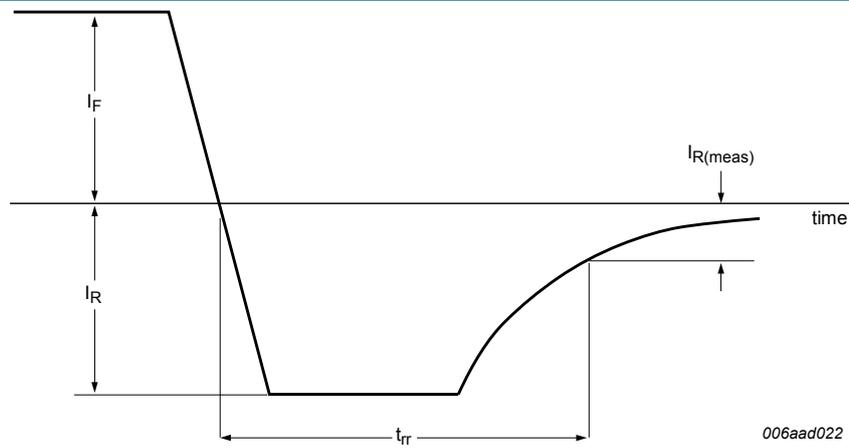


Fig. 13. Reverse recovery definition

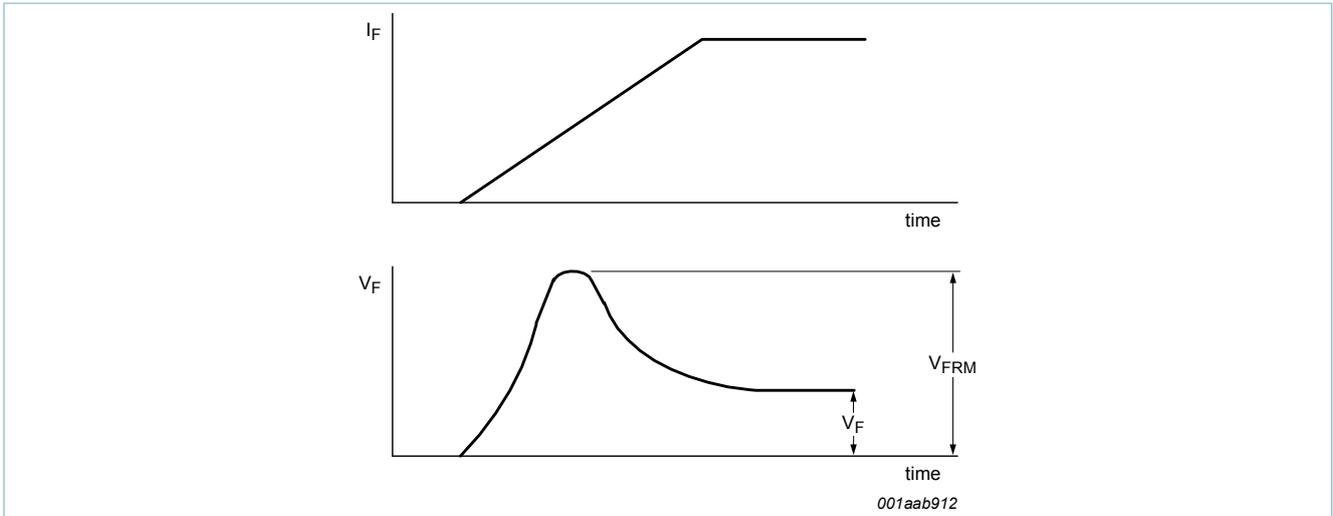


Fig. 14. Forward recovery definition

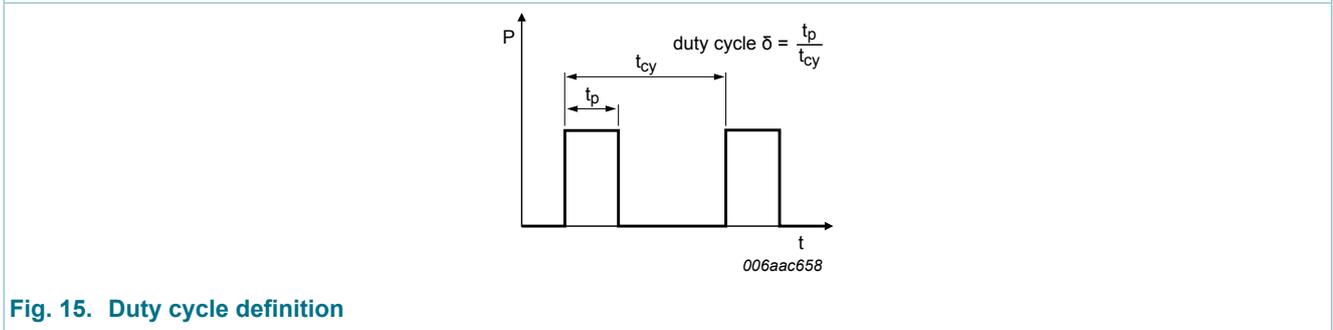


Fig. 15. Duty cycle definition

The current ratings for the typical waveforms are calculated according to the equations: $I_{F(AV)} = I_M \times \delta$ with I_M defined as peak current, $I_{RMS} = I_{F(AV)}$ at DC, and $I_{RMS} = I_M \times \sqrt{\delta}$ with I_{RMS} defined as RMS current.

11.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard Q101 - Stress test qualification for discrete semiconductors, and is suitable for use in automotive applications.

12. Package outline

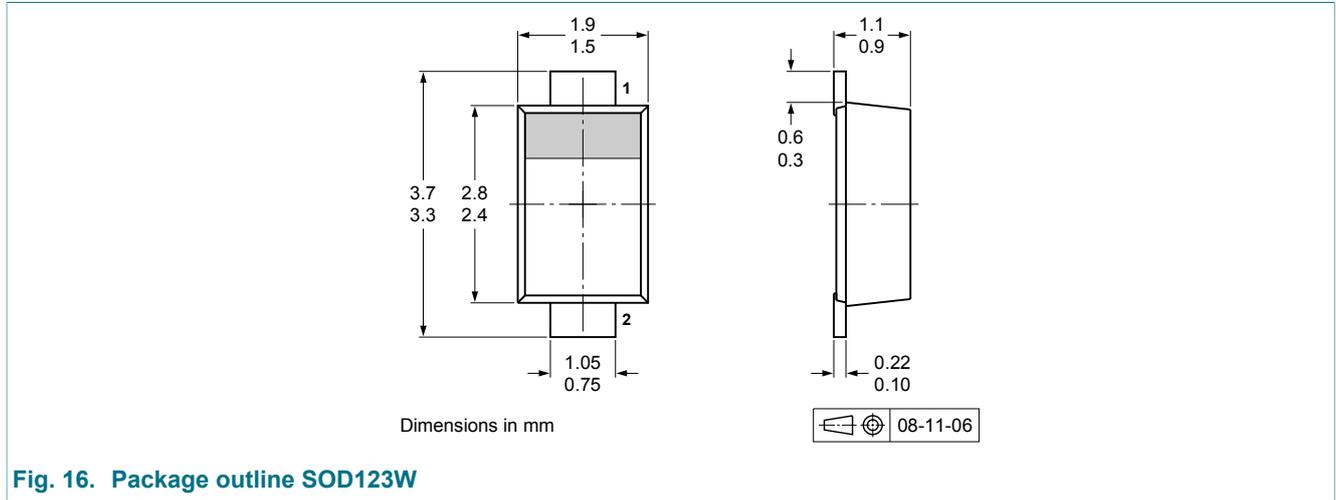


Fig. 16. Package outline SOD123W

13. Revision history

Table 8. Revision history

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PMEG6010ELR v.1	20131108	Preliminary data sheet	-	-

14. Legal information

14.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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